

G. Device & Process Modeling, Simulation and Reliability 분과

2020년 2월 13일(목), 09:00-10:30 / Room D (사파이어 II+III, 5층)

■ [TD1-G] Modeling of Semiconductor Devices

좌장: 홍성민 교수 (GIST), 이재우 교수 (고려대학교)

TD1-G-1 09:00-09:15	Analysis of Grain Boundary Dependent Memory Characteristics in Poly-Si 1T-DRAM SongYi Yoo ¹ , HyeonJeong Kim ¹ , In Man Kang ² , Seongjae Cho ³ , Wookyung Sun ¹ , and Hyungsoon Shin ¹ ¹ Department of Electronic and Electrical Engineering, Ewha Womans University, ² School of Electronics Engineering, Kyungpook National University, ³ Department of Electronic Engineering, Gachon University
TD1-G-2 09:15-09:30	Formation of 2D Electron Gas in undoped Si/SiGe Layer: Exploring the Feasibility of Quantum Gate Designs with a Modeling Study Ji-Hoon Kang ¹ , Chungheon Baek ² , Byung-Soo Choi ² , and Hoon Ryu ¹ ¹ KISTI, ² ETRI
TD1-G-3 09:30-09:45	Analog Activation Function for Non-linear Synaptic Device Based Neural Network Myungjun Kim, Chuljun Lee, Yubin Song, and Daeseok Lee Department of Electronic Materials Engineering, Kwangwoon University
TD1-G-4 09:45-10:00	Alternating Current-based Open Drain Method for Separate Extraction of Source and Drain Resistances in MOSFETs Han Bin Yoo, Haesung Kim, Jintae Yu, Yoon Ju Park, Sung-Jin Choi, Dae Hwan Kim, and Dong Myong Kim School of Electrical Engineering, Kookmin University
TD1-G-5 10:00-10:15	Gate-induced Drain Leakage Current Model of P-type Polycrystalline Silicon Thin Film Transistors Aged by Off-state Stress Ki Hwan Kim ^{1,2} , Hyo Jung Kim ^{1,3} , Soon Kon Kim ¹ , Mi Seon Seo ² , Hyunguk Cho ² , Youngmi Cho ² , Yongjo Kim ² , and Byung Deog Choi ¹ ¹ Department of Electrical and Computer Engineering, Sungkyunkwan University, ² Computer Aided Engineering Team, Samsung Display Company, ³ Technology of Reliability, OLED Business Samsung Display
TD1-G-6 10:15-10:30	Characterization of Spatial Distribution of Traps across the Substrate in Metal-Insulator-Semiconductor Structures with Band Bending Effect Jintae Yu, Han Bin Yoo, Haesung Kim, Yoon Ju Park, Sung-jin Choi, Dae Hwan Kim, and Dong Myong Kim School of Electrical Engineering, Kookmin University